Seal	rcn notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/065,293	LEE ET AL.	
Examiner	Art Unit	
Frank Duong	2616	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
Updated EAST Search (see printout)	9/7/2006	FD
Updated Inventorship Search (see printout)	9/7/2006	FD
Updated IEEE/Internet Search	9/7/2006	FD